

**Search Notes**

Application/Control No.

10/024,606

Examiner

Jia W. Lu

Applicant(s)/Patent under  
Reexamination

KAKU ET AL.

Art Unit

2634

**SEARCHED**

Class	Subclass	Date	Examiner
375	376	7/14/2005	JL
375	229	7/14/2005	JL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	376	7/14/2005	JL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	7/14/2005	JL